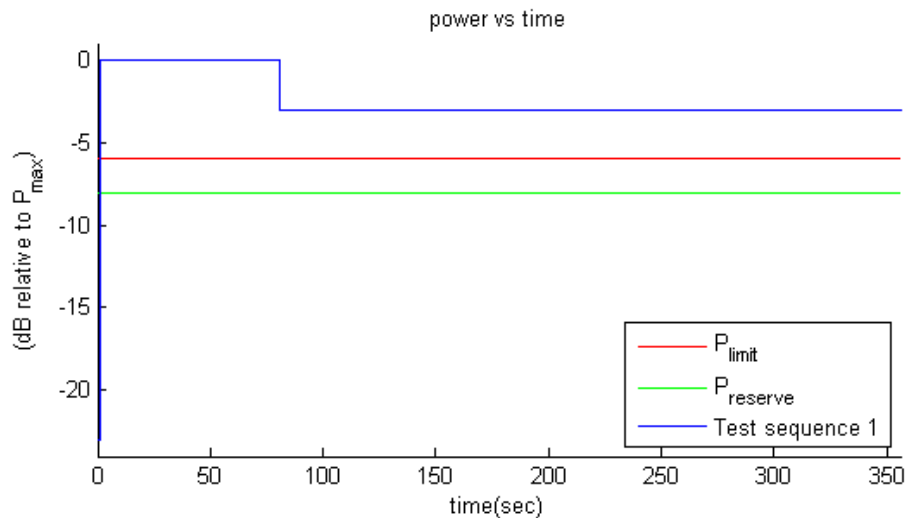


## APPENDIX E: TEST SEQUENCES

1. Test sequence is generated based on below parameters of the DUT:
  - a. Measured maximum power ( $P_{max}$ )
  - b. Measured Tx\_power\_at\_SAR\_design\_target ( $P_{limit}$ )
  - c. Reserve\_power\_margin (dB)
    - $P_{reserve}$  (dBm) = measured  $P_{limit}$  (dBm) – Reserve\_power\_margin (dB)
  - d. SAR\_time\_window (100s for FCC)
2. Test Sequence 1 Waveform:

Based on the parameters above, the Test Sequence 1 is generated with one transition between high and low Tx powers. Here, high power =  $P_{max}$ ; low power =  $P_{max}/2$ , and the transition occurs after 80 seconds at high power  $P_{max}$ . As long as the power enforcement is taking into effective during one 100s/60s time window, the validation test with this defined test sequence 1 is valid, otherwise, select other radio configuration (band/DSI within the same technology group) having lower  $P_{limit}$  for this test. The Test sequence 1 waveform is shown below:



**Figure E-1**  
**Test sequence 1 waveform**

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3. Test Sequence 2 Waveform:

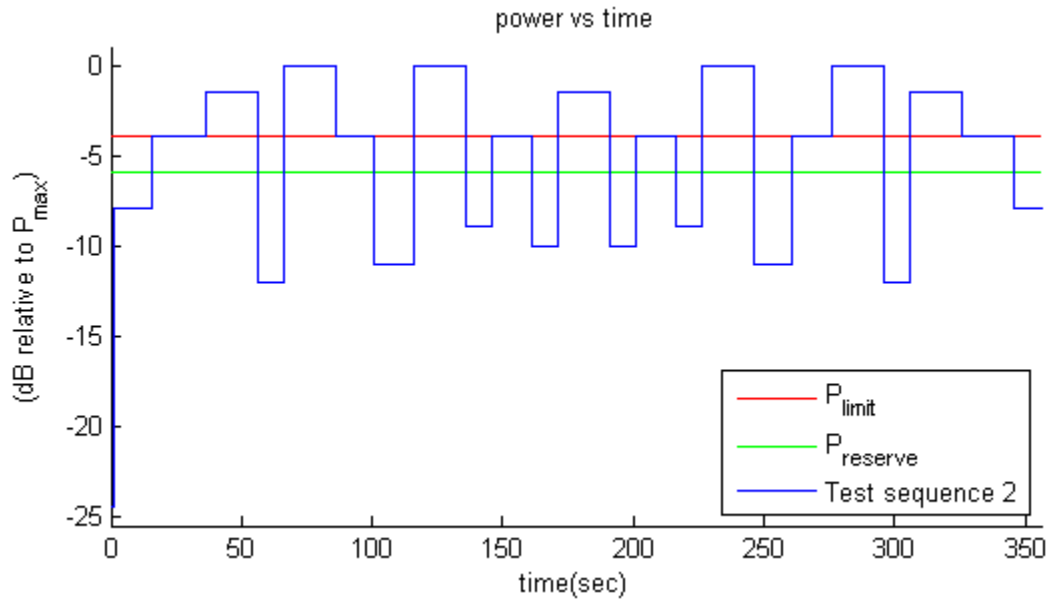
Based on the parameters described above, the Test Sequence 2 is generated as described in Table E-1, which contains two 170 second-long sequences (yellow and green highlighted rows) that are mirrored around the center row of 20s, resulting in a total duration of 360 seconds:

**Table E-1  
Test Sequence 2**

Time duration (seconds)	dB relative to $P_{limit}$ or $P_{reserve}$
15	$P_{reserve} - 2$
20	$P_{limit}$
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step
10	$P_{reserve} - 6$
20	$P_{max}$
15	$P_{limit}$
15	$P_{reserve} - 5$
20	$P_{max}$
10	$P_{reserve} - 3$
15	$P_{limit}$
10	$P_{reserve} - 4$
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step
10	$P_{reserve} - 4$
15	$P_{limit}$
10	$P_{reserve} - 3$
20	$P_{max}$
15	$P_{reserve} - 5$
15	$P_{limit}$
20	$P_{max}$
10	$P_{reserve} - 6$
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step
20	$P_{limit}$
15	$P_{reserve} - 2$

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The Test Sequence 2 waveform is shown in Figure E-2.



**Figure E-2**  
**Test sequence 2 waveform**

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